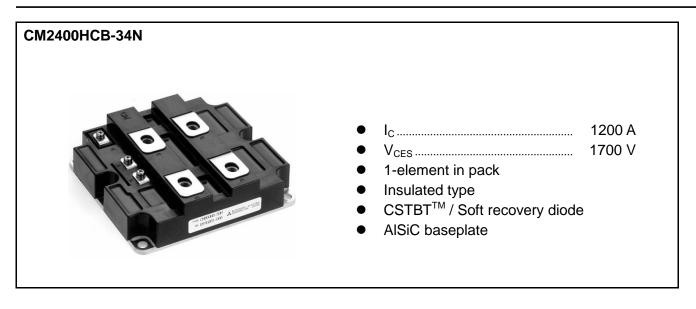


< High Voltage Insulated Gate Bipolar Transistor: HVIGBT >

CM1200HCB-34N

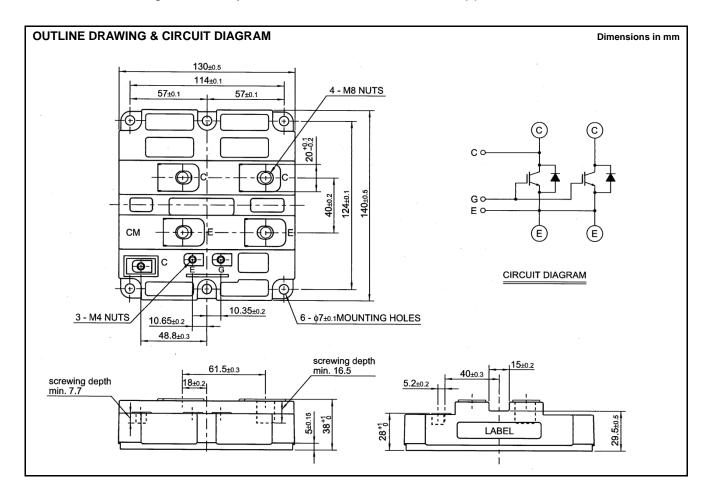
HIGH POWER SWITHCHING USE INSULATED TYPE

4th-Version HVIGBT (High Voltage Insulated Gate Bipolar Transistor) Modules



APPLICATION

Traction drives, High Reliability Converters / Inverters, DC choppers



MAXIMUM RATINGS

Symbol	Item	Conditions	Ratings	Unit
V _{CES}	Collector-emitter voltage	$V_{GE} = 0V, T_j = 25 ^{\circ}C$	1700	V
V_{GES}	Gate-emitter voltage	$V_{CE} = 0V, T_j = 25 ^{\circ}C$	± 20	V
Ic	Collector current	DC, $T_c = 80 ^{\circ}C$	1200	Α
I _{CRM}	Collector current	Pulse (Note 1)	2400	Α
I _E	(Note 2)	DC	1200	Α
I _{ERM}	Emitter current (NOTE 2)	Pulse (Note 1)	2400	Α
P _{tot}	Maximum power dissipation (Note 3)	T _c = 25 °C, IGBT part	8600	W
V_{iso}	Isolation voltage	RMS, sinusoidal, f = 60Hz, t = 1min.	4000	V
T_j	Junction temperature		− 40 ~ + 150	°C
T_jop	Operating temperature		−40 ~ +125	°C
T_{stg}	Storage temperature		− 40 ~ + 125	°C
t _{pSC}	Maximum short circuit pulse width	$V_{CC} = 1000V, V_{CE} \le V_{CES}, V_{GE} = 15V, T_j = 125^{\circ}C$	10	μs

ELECTRICAL CHARACTERISTICS

Cumbal	Item	Conditions		Limit			Unit
Symbol		Conditions		Min	Тур	Max	
I _{CES}	Collector cutoff current	$V_{CE} = V_{CES} V_{CE} = 0 V$	$T_j = 25 ^{\circ}C$			5	mA
ICES	Collector cutoff current		T _j = 125 °C		4.0	10	
$V_{GE(th)}$	Gate-emitter threshold voltage	$V_{CE} = 10 \text{ V}, I_{C} = 120 \text{ mA}, T_{j} = 25 \text{ °C}$		5.5	6.5	7.5	V
I _{GES}	Gate leakage current	$V_{GE} = V_{GES}, V_{CE} = 0V, T_j = 25^{\circ}C$		-0.5	_	0.5	μΑ
Cies	Input capacitance	V _{CF} = 10 V. V _{GF} = 0 V. f = 100 kHz		_	220	_	nF
C _{oes}	Output capacitance	02 1 7 02 1 7		_	12	_	nF
C _{res}	Reverse transfer capacitance	T _j = 25 °C		_	3.5	_	nF
Q_G	Total gate charge	$V_{CC} = 900 \text{ V}, I_{C} = 1200 \text{ A}, V_{GE} = \pm 15 \text{ V}$		_	15.2	_	μC
V _{CEsat}	Collector amittar acturation valtage	I _C = 1200 A (Note 4)	T _j = 25 °C	_	2.05	2.70	V
V CEsat	Collector-emitter saturation voltage	V _{GE} = 15 V	T _j = 125 °C	_	2.30	_	v
t _{d(on)}	Turn-on delay time	V _{CC} = 900 V, I _C = 1200 A		-		1.50	μs
t _r	Turn-on rise time	$V_{GE} = \pm 15 \text{ V}, R_{G(on)} = 1.1 \Omega$ $T_i = 125 \text{ °C}, L_s = 100 \text{ nH}$		_	_	0.60	μs
E _{on(10%)}	Turn-on switching energy (Note 5)	Inductive load		_	0.43	_	J
$t_{d(off)}$	Turn-off delay time	$V_{CC} = 900 \text{ V}, I_C = 1200 \text{ A}$		_	_	3.00	μs
t _f	Turn-off fall time		$V_{GE} = \pm 15 \text{ V}, R_{G(off)} = 2.0 \Omega$		_	0.60	μs
E _{off(10%)}	Turn-off switching energy (Note 5)	$T_j = 125 ^{\circ}\text{C}$, $L_s = 100 ^{\circ}\text{nH}$ Inductive load	_	0.32	_	J	
.,	(Note 2)	I _E = 1200 A ^(Note 4)	T _j = 25 °C	_	2.20	3.00	.,
V _{EC}	Emitter-collector voltage (Note 2)	V _{GE} = 0 V	T _j = 125 °C	_	1.85	_	V
t _{rr}	Reverse recovery time (Note 2)	V _{CC} = 900 V, I _E = 1200 A		_	_	1.50	μs
Q _{rr}	Reverse recovery charge (Note 2)	V_{GE} = ±15 V, $R_{G(on)}$ = 1.1 Ω T_{j} = 125 °C, L_{s} = 100 nH Inductive load		_	410	_	μC
E _{rec(10%)}	Reverse recovery energy (Note 2) (Note 5)			_	0.29		J

THERMAL CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
		Conditions	Min	Тур	Max	Unit
$R_{th(j-c)Q}$	Thermal resistance	Junction to Case, IGBT part	1	_	14.0	K/kW
$R_{th(j-c)D}$		Junction to Case, FWDi part	1	_	21.0	K/kW
R _{th(c-s)}	Contact thermal resistance	Case to heat sink, λ _{grease} = 1W/m•k, D _(c-s) = 100μm	_	10.0	_	K/kW

< High Voltage Insulated Gate Bipolar Transistor: HVIGBT >

CM1200HCB-34N

HIGH POWER SWITHCHING USE INSULATED TYPE

4th-Version HVIGBT (High Voltage Insulated Gate Bipolar Transistor) Modules

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions	Limits			l lait
		Conditions	Min	Тур	Max	Unit
M_t	Mounting torque	M8 : Main terminals screw	7.0		13.0	N⋅m
Ms		M6: Mounting screw	3.0	-	6.0	N⋅m
M_t		M4 : Auxiliary terminals screw	1.0	I	2.0	N⋅m
m	Mass		1	1.5	l	kg
CTI	Comparative tracking index		600			_
da	Clearance		19.5	I	l	mm
d _s	Creepage distance		32.0	I	l	mm
L _{P CE}	Parasitic stray inductance			15.0	1	nΗ
R _{CC'+EE'}	Internal lead resistance	$T_C = 25 ^{\circ}C$	1	0.21	I	mΩ

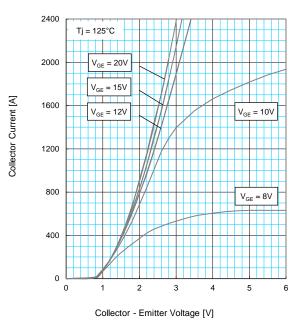
Note1. Pulse width and repetition rate should be such that junction temperature (T_i) does not exceed T_{jopmax} rating.

- 2. The symbols represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWD_i).
- 3. Junction temperature (T_j) should not exceed T_{jmax} rating (150°C).
- 4. Pulse width and repetition rate should be such as to cause negligible temperature rise.
- 5. $E_{on(10\%)}$ / $E_{off(10\%)}$ / $E_{rec(10\%)}$ are the integral of 0.1 V_{CE} x 0.1 I_C x dt.

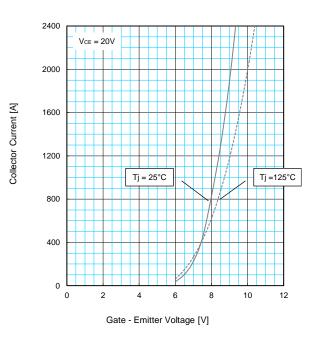
PERFORMANCE CURVES

INSULATED TYPE

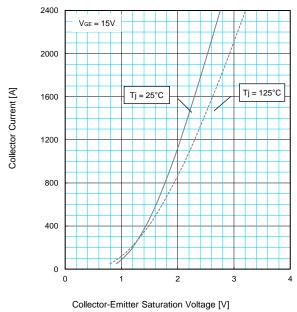
OUTPUT CHARACTERISTICS (TYPICAL)



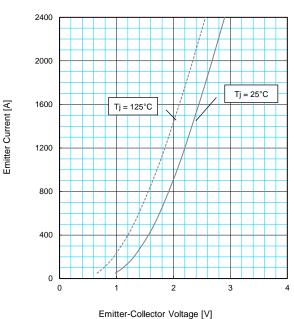
TRANSFER CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



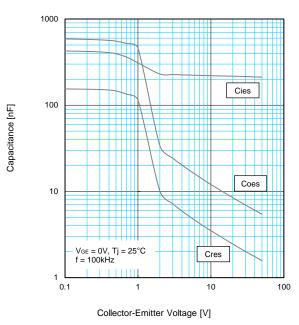
FREE-WHEEL DIODE FORWARD CHARACTERISTICS (TYPICAL)



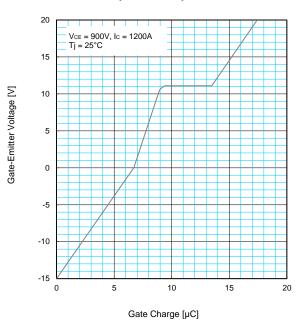
PERFORMANCE CURVES

INSULATED TYPE

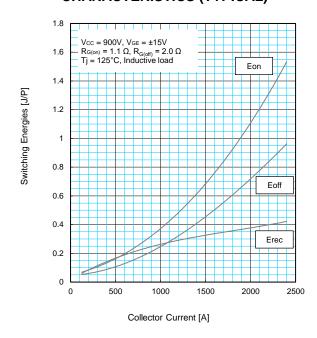
CAPACITANCE CHARACTERISTICS (TYPICAL)



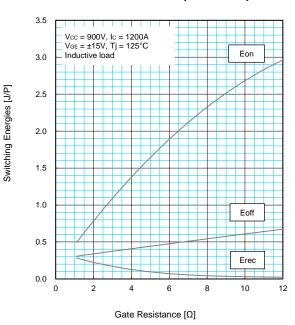
GATE CHARGE CHARACTERISTICS (TYPICAL)



HALF-BRIDGE SWITCHING ENERGY CHARACTERISTICS (TYPICAL)



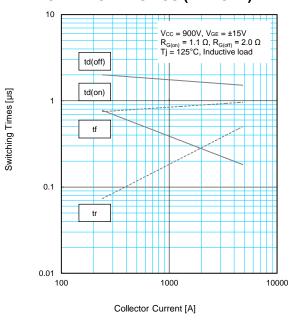
HALF-BRIDGE SWITCHING ENERGY CHARACTERISTICS (TYPICAL)



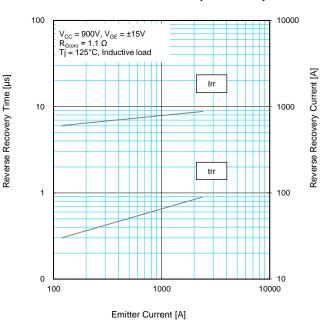
PERFORMANCE CURVES

INSULATED TYPE

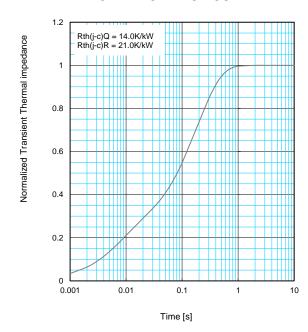
HALF-BRIDGE SWITCHING ENERGY CHARACTERISTICS (TYPICAL)



FREE-WHEEL DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS



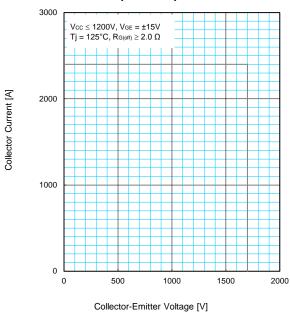
$$Z_{th(j-c)}(t) = \sum_{i=1}^{n} R_{i} \left\{ 1 - exp^{\left(-\frac{t}{\tau_{i}}\right)} \right\}$$

Collector Current [A]

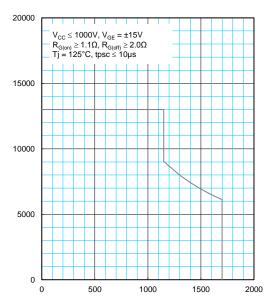
PERFORMANCE CURVES

INSULATED TYPE

REVERSE BIAS SAFE OPERATING AREA (RBSOA)

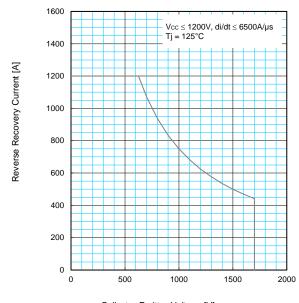


SHORT CIRCUIT SAFE OPERATING AREA (SCSOA)



Collector-Emitter Voltage [V]

FREE-WHEEL DIODE REVERSE RECOVERY SAFE OPERATING AREA (RRSOA)



Collector-Emitter Voltage [V]

4th-Version HVIGBT (High Voltage Insulated Gate Bipolar Transistor) Modules

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